

Date Searched: 3/22/2006  
Databases Searched: USPAT, USPGPUB  
Plurals: ON  
Terms Searched:  
L1 (programmable adj3 (device or array)) or fpga or pga or pld or cpld  
L2 (gate near5 leak\$4)  
L3 (power or current or voltage) same (consumption or dissipat\$4 or consum\$2 or leak\$4)  
L4 2 same 3  
L5 1 and 4  
Results: 385 hits  
L6 716/1-18.ccls. and 5 and @pd>20060218  
Results: 0 hit

Date Searched: 2/18/2006  
Databases Searched: USPAT, USPGPUB  
Plurals: ON  
Terms Searched:  
L1 (programmable adj3 (device or array)) or fpga or pga or pld or cpld  
L2 (gate near5 leak\$4)  
L3 (power or current or voltage) same (consumption or dissipat\$4 or consum\$2 or leak\$4)  
L4 2 same 3  
L5 1 and 4  
Results: 385 hits  
L6 716/1-18.ccls. and 5 and @pd>20051223  
Results: 1 hit

US 6993737 B1                      USPAT Anderson; Jason H. et al.                      716/5

Date Searched: 12/23/2005  
Databases Searched: USPAT, USPGPUB  
Plurals: ON  
Terms Searched:  
L1 (programmable adj3 (device or array)) or fpga or pga or pld or cpld  
L2 (gate near5 leak\$4)  
L3 (power or current or voltage) same (consumption or dissipat\$4 or consum\$2 or leak\$4)  
L4 2 same 3  
L5 1 and 4  
Results: 385 hits  
L6 716/1-18.ccls. and 5  
Results: 6 hits  
  
L7 (power or current or voltage) near5 (dissipat\$4 or leak\$4)  
L8 1 and 7 and 716/1-18.ccls.  
Results: 169 hits  
L9 (gate or gated or gating) same 7  
L10 8 and 9  
Results: 65 hits  
L11 stack\$3 near3 transistor  
L12 10 and 11  
Results: 0 hit  
L13 (statistic\$2 or probability or likelihood or likely) same (low or high or on or off or active or inactive or enable\$1 or disable\$1)  
L14 13 same 7  
L15 1 and 9 and 14

Results: 35 hits

L16 1 and 9 and 11

Results: 110 hits

L17 16 and 716/1-18.ccls.

Results: 0 hit

L18 (statistic\$2 or probability or likelihood or likely) same stack\$3

L19 1 and 9 and 18

Results: 22 hits

L20 1 and (9 same 11)

Results: 3 hits

US 20040216074 A1	US-PGPUB	Hart, Michael J. et al.	716/16
US 6324678 B1	USPAT Dangelo; Carlos et al.		716/18
US 6038386 A	USPAT Jain; Gitu		716/16
US 5712790 A	USPAT Ditlow; Gary Stephen et al.		716/2
US 6345379 B1	USPAT Khouja; Adel et al.		716/4

US 20050091629 A1	US-PGPUB	Eisenstadt, Robert et al.	716/13
US 6075932 A	USPAT Khouja; Adel et al.		716/4
US 20050097496 A1	US-PGPUB	Koike, Hanpei et al.	716/13
US 20040025135 A1	US-PGPUB	Hart, Michael J. et al.	716/16
US 6777978 B2	USPAT Hart; Michael J. et al.		326/38
US 6681376 B1	USPAT Balasinski; Artur et al.		716/4
US 6289488 B1	USPAT Dave; Bharat P. et al.		716/1
US 6230303 B1	USPAT Dave; Bharat P.		716/7

US 6562638 B1	USPAT Balasinski; Artur et al.		438/14
US 20050198606 A1	US-PGPUB	Gupta, Sanjay et al.	716/18
US 20050071800 A1	US-PGPUB	Liu, Ming-Kang	716/18
US 20040250231 A1	US-PGPUB	Killian, Earl A. et al.	716/18
US 20030208733 A1	US-PGPUB	Sokolov, Serguei A.	716/4
US 6871172 B1	USPAT Sanders; Lester		703/14
US 6480815 B1	USPAT Olson; Janet et al.		703/14
US 6195630 B1	USPAT Mauskar; Ashutosh S. et al.		703/18
US 5949689 A	USPAT Olson; Janet et al.		703/14
US 5508939 A	USPAT Kim; Jaeseok et al.		716/7

Stacked transistors

US 5694055 A	USPAT Shimanek; Schuyler E.		326/37
US 6868014 B1	USPAT Melik-Martirosian; Ashot et al.		365/185.28

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 (programmable adj3 (device or array)) or fpga or pga or pld or cpld

L2 (power or current or voltage) near5 (dissipat\$4 or leak\$4)

L3 (gate or gated or gating) same 2

L4 1 and 3

Results: 31 hits

L5 stack\$3 near3 transistor

L6 4 and 5

Results: 1 hit

L7 (statistic\$2 or probability or likelihood or likely) same stack\$3

L8 1 and 3 and 7

Results: 1 hit

L9 (statistic\$2 or probability or likelihood or likely) same (low or high or on or off or active or inactive or enable\$1 or disable\$1)  
L10 1 and 3 and 9  
Results: hits

EP 416903 A2	A2, A3	EPO	WHITTEN, RALPH G et al.
NN9603163		IBM_TDB	
NN8803247		IBM_TDB	
US 6871172 B		DERWENT	SANDERS, L
US 6768338 B		DERWENT	KONDAPALLI, V M et al.
US 5576636 A		DERWENT	BAUCOM, T L
EP 667679 A	A1, B1	DERWENT	HANWOOD, M G
NN940169		IBM_TDB	

Database Searched: IEE/IEEE XPlore

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and ((power or current or voltage) <near/5> (dissipat\* or leak\*)) and (gate or gated or gating)

Results: Your search matched **89** of **1286976** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and ((power or current or voltage) <near/5> (dissipat\* or leak\*)) and (gate or gated or gating) and (stack\* <near/5> transistor)

Results: Your search matched **1** of **1286976** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and ((power or current or voltage) <near/5> (dissipat\* or leak\*)) and (statistic\* or probability or likelihood or likely) and stack\*

Results: Your search matched **0** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and ((power or current or voltage) <near/5> (dissipat\* or leak\*)) and ((statistic\* or probability or likelihood or likely) <near/15> (low or high or on or off or active or inactive or enable\* or disable\*))

Results: Your search matched **4** of **1286976** documents.